## SN74F377A OCTAL D-TYPE FLIP-FLOP WITH CLOCK ENABLE SDFS018D – D2932, MARCH 1987 – REVISED OCTOBER 1993

<ul> <li>Contains Eight D-Type Flip-Flops</li></ul>	DW OR N PACKAGE
With Single-Rail Outputs	(TOP VIEW)
<ul> <li>Clock Enable Latched to Avoid False Clocking</li> </ul>	$\begin{array}{c c} \hline CE & 1 & 20 \\ 1Q & 2 & 19 \\ \end{array} V_{CC}$
<ul> <li>Applications Include:</li></ul>	1D [ 3 18 ] 8D
Buffer/Storage Registers	2D [ 4 17 ] 7D
Shift Registers	2Q [ 5 16 ] 7Q
Pattern Generators	3Q [ 6 15 ] 6Q
<ul> <li>Buffered Common Enable Input</li> </ul>	3D [] 7 14 ] 6D
<ul> <li>Package Options Include Plastic</li></ul>	4D [ 8 13 ] 5D
Small-Outline Packages and Standard	4Q [ 9 12 ] 5Q
Plastic 300-mil DIPs	GND [ 10 11 ] CLK

## description

The SN74F377A is a monolithic, positive-edge-triggered, octal, D-type flip-flop with clock enable inputs. The SN74F377A features a latched clock enable (CE) input.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse if  $\overline{CE}$  is low. Clock triggering occurs at a particular voltage level and is not directly related to the positive-going pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output. The circuits are designed to prevent false clocking by transitions at the  $\overline{CE}$  input.

The SN74F377A is characterized for operation from 0°C to 70°C.

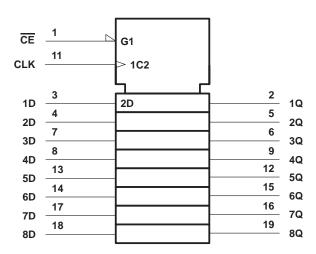
(each flip-flop)							
	INPUTS	OUTPUT					
CE	CLK	D	Q				
Н	Х	Х	Q <sub>0</sub>				
L	$\uparrow$	Н	н				
L	$\uparrow$	L	L				
Х	L	Х	Q <sub>0</sub>				

FUNCTION TABLE



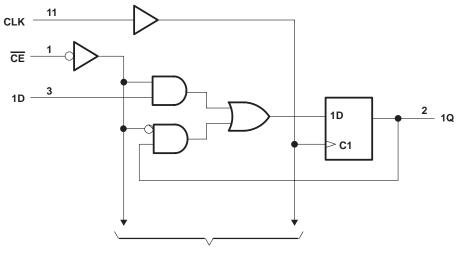
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## logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



**To Seven Other Channels** 

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	–1.2 V to 7 V
Input current range	30 mA to 5 mA
Voltage range applied to any output in the high state	$\dots$ –0.5 V to V <sub>CC</sub>
Current into any output in the low state	40 mA
Operating free-air temperature range	0°C to 70°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input-voltage ratings may be exceeded provided the input-current ratings are observed.



## SN74F377A OCTAL D-TYPE FLIP-FLOP WITH CLOCK ENABLE

SDFS018D - D2932, MARCH 1987 - REVISED OCTOBER 1993

## recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
IIК	Input clamp current			- 18	mA
ЮН	High-level output current			- 1	mA
IOL	Low-level output current			20	mA
TA	Operating free-air temperature	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	Т	TEST CONDITIONS		түр†	MAX	UNIT
Veu	$V_{CC} = 4.5 V,$	I <sub>OH</sub> = - 1 mA	2.5	3.4		V
Vон	V <sub>CC</sub> = 4.75 V,	I <sub>OH</sub> = - 1 mA	2.7			v
V <sub>OL</sub>	$V_{CC} = 4.5 V,$	I <sub>OL</sub> = 20 mA		0.3	0.5	V
lı	$V_{CC} = 0,$	V <sub>I</sub> = 7 V			0.1	mA
Чн	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20	μA
Ι <sub>ΙL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.5 V			- 0.6	mA
los‡	V <sub>CC</sub> = 5.5 V,	VO = 0	- 60		- 150	mA
ІССН	V <sub>CC</sub> = 5.5 V,	See Note 2		55	72	mA
ICCL	V <sub>CC</sub> = 5.5 V,	See Note 3		70	90	mA

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

<sup>‡</sup> Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTES: 2. I<sub>CCH</sub> is measured after applying a momentary ground, then 4.5 V, to the clock input with all data inputs at 4.5 V and the enable input

at GND.

3. ICCL is measured after applying a momentary ground, then 4.5 V, to the clock input with all data and enable inputs at GND.

### timing requirements

				= 5 V, 25°C	V <sub>CC</sub> = 4.5 T <sub>A</sub> = MIN t	V to 5.5 V, o MAX§	UNIT
			MIN	MAX	MIN	MAX	
fclock	Clock frequency		0	110	0	110	MHz
tw	Pulse duration		4		5		ns
	t <sub>su</sub> Setup time before CLK↑	Data high or low	2		2		ns
t <sub>su</sub>		CE high	2.5		2.5		
		CE low	4		4.5		
t <sub>h</sub>		Data high or low	1		1		
	Hold time after CLK↑	CE high or low	0		0		ns

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



## switching characteristics (see Note 4)

PARAMETER	FROM (INPUT)	$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 Ω, T <sub>A</sub> = 25°C		<b>,</b> <u>),</u>	UNIT		
			MIN	TYP	MAX	MIN	MAX	
fmax			110	125		110		MHz
<sup>t</sup> PLH	CLK	Any Q	4	6.5	8.5	4	10	ns
<sup>t</sup> PHL		Ally Q	4	7	9	4	10.5	115

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 4: Load circuit and waveforms are shown in Section 1.



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